

AMENDMENTS TO THE SPECIFICATION:

Please replace the current title of this application as follows:

-- SEMICONDUCTOR DEVICE TEST PROBE HAVING IMPROVED TIP
PORTION. --

Please replace the paragraph beginning on page 1, line 4 and ending on page 1,
line 6, with the following amended paragraph:

-- This application is a continuation of Application No. 09/810,247, filed on
March 19, 2001, and is based on Application No. 10-245881, filed in Japan on August 31,
1998 and Application No. ~~10-245881~~ 11-241690, filed in Japan on August 27, 1999, the
contents of which are hereby incorporated by reference. --